R4 🛛 9

10

TE

12 🛛 E4

11 RE

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<ul> <li>Suitable for IEEE Standard 896 Applications<sup>†</sup></li> </ul>	SN75ALS056 DW OR N PACKAGE (TOP VIEW)
<ul> <li>SN75ALS056 is an Octal Transceiver</li> </ul>	A1 [ 1 20] B1
<ul> <li>SN75ALS057 is a Quad Transceiver</li> </ul>	A2 2 19 B2
<ul> <li>High-Speed Advanced Low-Power Schottky (ALS) Circuitry</li> </ul>	A3 [ 3 <sub>18</sub> ] B3 A4 [ 4 17 ] B4
<ul> <li>Low Power Dissipation: 52.5 mW/Channel Max</li> </ul>	V <sub>CC</sub> 5 16 GND A5 6 15 B5
High-Impedance pnp Inputs	A6 [] 7 14 [] B6 A7 [] 8 13 [] B7
<ul> <li>Logic-Level 1-V Bus Swing Reduces Power Consumption</li> </ul>	A7 [ 0 13 ] B7 A8 [ 9 12 ] B8 CS [ 10 11 ] T/R
<ul> <li>Trapezoidal Bus Output Waveform Reduces Noise Coupling to Adjacent Lines</li> </ul>	
<ul> <li>Power-Up/Power-Down Protection (Glitch Free)</li> </ul>	SN75ALS057 DW OR N PACKAGE (TOP VIEW)
<ul> <li>Open-Collector Driver Outputs Allow Wired-OR Connections</li> </ul>	D1 [ 1 20] B1 R1 [ 2 19] E1
<ul> <li>Designed to Be a Faster, Lower-Power Functional Equivalent of National DS3896,</li> </ul>	D2 0 3 18 B2 R2 4 17 E2
DS3897	V <sub>CC</sub> [ 5 16 ] GND D3 [ 6 15 ] B3
description	R3 🛛 7 14 🗋 E3
	D4 🛛 8 13 🗍 B4

The SN75ALS056 is an eight-channel, monolithic, high-speed, advanced low-power Schottky (ALS) device designed for two-way data communication in a densely populated backplane. The SN75ALS057 is a four-channel version with independent driver-input (Dn) and receiver-output (Rn) pins and a separate driver disable for each driver (En).

These transceivers feature open-collector driver outputs with series Schottky diodes to reduce capacitive loading to the bus. By using a 2-V pullup termination on the bus, the output signal swing is approximately 1 V, which reduces the power necessary to drive the bus load capacitance. The driver outputs generate trapezoidal waveforms that reduce crosstalk between channels. The drivers are capable of driving an equivalent dc load as low as 18.5  $\Omega$ . The receivers have internal low-pass filters to further improve noise immunity.

The SN75ALS056 and SN75ALS057 are characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

<sup>†</sup> The transceivers are suitable for IEEE Standard 896 applications to the extent of the operating conditions and characteristics specified in this data sheet.

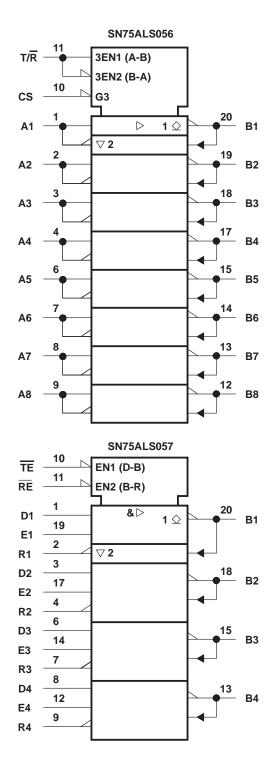
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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#### logic symbol<sup>†</sup>

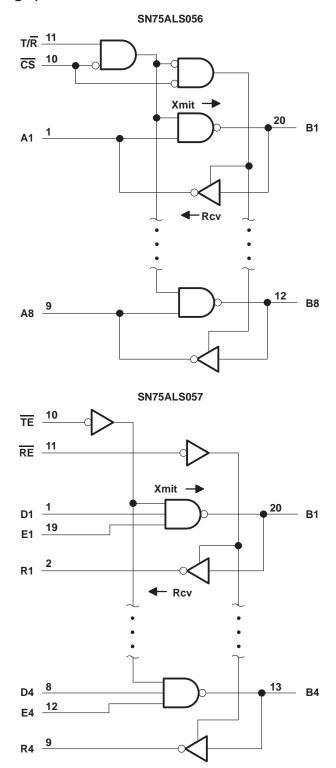


<sup>†</sup> These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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#### logic diagram (positive logic)



<sup>†</sup> These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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#### **Function Tables**

SN75ALS056 TRANSMIT/RECEIVE

CONT	ROLS	CHAN	NELS
CS	T/R	<b>A</b> ←	→ <b>B</b>
L	Н	T(A	B)
L	L	R(B	A)
н	Х	C	)

#### SN75ALS057 TRANSMIT/RECEIVE

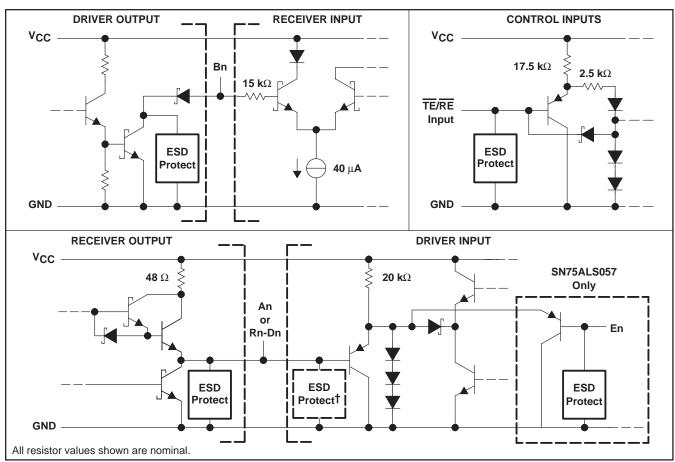
C	ONTROL	S		CHAN	INELS	
TE	RE	En	D	В	В	R
L	L	L	0	)	F	२
L	L	Н	1	Г	F	र
L	Н	L		)	[	)
L	Н	Н	ר	Г	[	)
н	L	Х		)	F	र
Н	Н	Х		)	[	)

H = high level, L = low level, R = receive, T = transmit, D = disable, X = irrelevant

Direction of data transmission is from An to Bn for the SN75ALS056 and from Dn to Bn for the SN75ALS057. Direction of data reception is from Bn to An for the SN75ALS056 and from Bn to Rn for the SN75ALS057. Data transfer is inverting in both directions.



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#### schematics of inputs and outputs

<sup>†</sup> Additional ESD protection is on the SN75ALS057, which has separate receiver-output and driver-input pins.

#### absolute maximum ratings over operating free-air temperature (unless otherwise noted)<sup>‡</sup>

Supply voltage, V <sub>CC</sub> (see Note 1)
Control input voltage, V <sub>1</sub> 5.5 V
Driver input voltage, V <sub>1</sub> 5.5 V
Driver output voltage, V <sub>O</sub> 2.5 V
Receiver input voltage, V <sub>1</sub> 2.5 V
Receiver output voltage, V <sub>O</sub> 5.5 V
Continuous total power dissipation Table Continuous total power dissipation Rating Table
Storage temperature range, T <sub>stg</sub>
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW or N package
<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and
functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not

implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Voltage values are with respect to network ground terminal.



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DISSIPATION RATING TABLE										
PACKAGE	$T_A \le 25^{\circ}C$ POWER RATING	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING							
DW	1025 mW	8.2 mW/°C	656 mW	_						
N	1150 mW	9.2 mW/°C	736 mW	—						

#### recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.75	5	5.25	V
High-level driver and control input voltage, VIH	2			V
Low-level driver and control input voltage, VIL			0.8	V
Bus termination voltage	1.9		2.1	V
Operating free-air temperature, T <sub>A</sub>	0		70	°C

# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			TEAT CONDITIONAT	SN	75ALS0	56	
	PARAMETER		TEST CONDITIONS <sup>†</sup> MIN TYP <sup>†</sup>		-1.5 1.69 0.5 1.2 40 100 -400	MAX	UNIT
VIK	Input clamp voltage at An,	T/R, or CS	II = -18 mA			-1.5	V
VIT	Receiver input threshold voltage at Bn			1.405		1.69	V
VOH			Bn at 1.2 V, <del>CS</del> at 0.8 V, T/ <del>R</del> at 0.8V, I <sub>OH</sub> = – 400 μA	2.4			V
		An	Bn at 2 V , <del>CS</del> at 0.8 V, T/ <del>R</del> at 0.8 V, I <sub>OL</sub> = 16 mA			0.5	
VOL	Low-level output voltage	Bn	An at 2 V, $\overline{CS}$ at 0.8 V, T/ $\overline{R}$ at 2 V, V <sub>L</sub> = 2 V, R <sub>L</sub> =18.5 Ω, See Figure 1	0.75		V 1.2	V
		An, T/ $\overline{R}$ or $\overline{CS}$	VI = VCC			40	
ЧΗ	High-level input current	Bn	V <sub>I</sub> = 2 V, V <sub>CC</sub> <u>=</u> 0 or 5.25 V, An at 0.8 V, T/R at 0.8 V			100	μA
١ <sub>IL</sub>	Low level input current at	An, T/R, or CS	$V_I = 0.4 V$			-400	μA
IOS	Short-circuit output current at An		An at 0, Bn at 1.2 V, CS at 0.8 V, T/R at 0.8 V	-40		-120	mA
ICC	Supply current					75	mA
C <sub>O(B)</sub>	Driver output capacitance				4.5		pF

<sup>†</sup> Typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> =  $25^{\circ}$ C.



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# electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	SN	75ALS0	57	UNIT
	PARAMETER		TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
VIK	Input clamp voltage at Dn, En, TE, or RE		I <sub>I</sub> = -18 mA			-1.5	V
VIT	Receiver input threshold voltage	at Bn		1.41		1.69	V
VOH	High-level output voltage at Rn		Bn at 1.2 V, <del>RE</del> at 0.8 V, I <sub>OH</sub> = -400 μA	2.4			V
		Rn	Bn at 2 V, <del>RE</del> at 0.8 V, I <sub>OL</sub> = 16 mA			0.5	
V <sub>OL</sub>	V <sub>OL</sub> Low-level output voltage	Bn	Dn at 2 V, En at 2 V, TE at 0.8 V, V <sub>L</sub> = 2 V, R <sub>L</sub> = 18.5 Ω, See Figure 1	0.75		1.2	V
		<u>Dn</u> , En <u>,</u> TE, or RE	VI = VCC			40	
ΙΗ	High-level input current	Bn	V <sub>I</sub> = 2 V, V <sub>CC</sub> = 0 or 5.25 V, <u>Dn</u> at 0.8 V, En at 0.8 V, TE at 0.8 V			100	μA
۱ <sub>IL</sub>	Low-level input current at Dn, Er	, TE, or RE	$V_I = 0.4 V$			-400	μA
IOS	Short-circuit output current at Rn		<u>Rn</u> at 0, Bn at 1.2 V, RE at 0.8 V	-40		-120	mA
ICC	Supply current					40	mA
C <sub>O(B)</sub>	Driver output capacitance				4.5		pF

<sup>†</sup>Typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		TO	TEST CONDITIONS	-	SN75ALS056 DRIVER		UNIT		
		(INPUT)	(OUTPUT)		MIN	түр†	MAX			
<sup>t</sup> PLH1	Propagation delay time, low-to-high-level output		Bn	An and $T/\overline{R}$ at 2 V, V <sub>L</sub> = 2 V, B: 1 = 18 O C = -30 pF			24	20		
<sup>t</sup> PHL1	Propagation delay time, high-to-low-level output	03	DI	$R_L 1 = 18 \Omega_r$ , $C_L = 30 pF$ , $R_L 2$ not connected, See Figure 2			20	ns		
<sup>t</sup> PLH2	Propagation delay time, low-to-high-level output	An	Bn	$\overline{CS}$ at 0.8 V, T/ $\overline{R}$ at 2 V, V <sub>L</sub> = 2 V, R <sub>L</sub> 1 = 18 Ω,			19	20		
<sup>t</sup> PHL2	Propagation delay time high-to-low-level output		DII	$R_L2$ not connected, $C_L = 30 pF$ , See Figure 2,			18	ns		
<sup>t</sup> PLH3	Propagation delay time, low-to-high-level output			Bn	$V_{I(An)} = 5 V, CS at 0.8 V,$ $R_{L}1 = 18 \Omega, C_{L} = 30 pF,$			25	20	
<sup>t</sup> PHL3	Propagation delay time, high-to-low-level output	T/R	BU		ווס	$R_L2$ not connected, $V_L = 2 V$ , See Figure 3,			35	ns
<sup>t</sup> TLH	Transition time, low-to-high-level output	An	$\overline{CS} \text{ at } 0.8 \text{ V}, \text{ T/R} \text{ at } 2 \text{ V},$ $V_{L} = 2 \text{ V}, \text{ C}_{L} = 30 \text{ pF},$		1	3	11	ns		
<sup>t</sup> THL	Transition time, high-to-low-level output		BU	Bn	$R_{L}^{-1} = 18 \Omega$	$R_L 1 = 18 \Omega$ , $R_L 2$ not connected, See Figure 2	1	3	6	115

† Typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ 



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# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75A RECE		UNIT
			(001201)		MIN MAX		
<sup>t</sup> PLH4	Propagation delay time, low-to-high-level output	Bn	An	$\overline{\text{CS}}$ at 0.8 V, T/ $\overline{\text{R}}$ at 0.8 V, R <sub>L</sub> 1 = 390 Ω,		18	ns
<sup>t</sup> PHL4	Propagation delay time, high-to-low-level output	Ы	АП	$R_L 2 = 1.6 \text{ k}\Omega$ , $C_L = 30 \text{ pF}$ , See Figure 4		18	115
<sup>t</sup> PLZ1	Output disable time from low level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, V <sub>I(Bn)</sub> = 2 V, V <sub>L</sub> = 5 V, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 not connected, C <sub>L</sub> = 15 pF, See Figure 3		20	ns
<sup>t</sup> PZL1	Output enable time to low level	T/R	An	$\label{eq:cs} \begin{array}{l} \overline{\text{CS}} \text{ at } 0.8 \ \text{V}, \ \text{V}_{I(Bn)} = 2 \ \text{V}, \ \text{V}_{L} = 5 \ \text{V}, \\ \text{R}_{L}1 = 390 \ \Omega, \ \text{R}_{L}2 = 1.6 \ \text{k}\Omega, \\ \text{C}_{L} = 30 \ \text{pF}, \ \text{See Figure } 3 \end{array}$		40	ns
<sup>t</sup> PHZ1	Output disable time from high level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, V <sub>I(Bn)</sub> = 0, V <sub>L</sub> = 0, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 not connected, C <sub>L</sub> = 15 pF, See Figure 3		17	ns
<sup>t</sup> PZH1	Output enable time to high level	T/R	An	$\overline{\text{CS}}$ at 0.8 V, VI <sub>(Bn</sub> ) = 0, V <sub>L</sub> = 0, R <sub>L</sub> 1 not connected, R <sub>L</sub> 2 = 1.6 kΩ, C <sub>L</sub> = 30 pF, See Figure 3		15	ns
<sup>t</sup> PLZ2	Output disable time from low level	CS	An	Bn at 2 V, T/ $\overline{R}$ at 0.8 V, C <sub>L</sub> = 5 pF, V <sub>L</sub> = 5 V, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 not connected, See Figure 5		18	ns
<sup>t</sup> PZL2	Output enable time to low level	CS	An	Bn at 2 V, T/ $\overline{R}$ at 0.8 V, C <sub>L</sub> = 30 pF, V <sub>L</sub> = 5 V, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 = 1.6 k $\Omega$ , See Figure 5		15	ns
<sup>t</sup> PHZ2	Output disable time from high level	CS	An	Bn at 0.8 V, T/ $\overline{R}$ at 0.8 V, C <sub>L</sub> = 5 pF, V <sub>L</sub> = 0, R <sub>L</sub> 1 = 390 Ω, R <sub>L</sub> 2 not connected, See Figure 5		8	ns
<sup>t</sup> PZH2	Output enable time to high level	CS	An	Bn at 0.8 V, T/ $\overline{R}$ at 0.8 V, C <sub>L</sub> = 30 pF, V <sub>L</sub> = 0, R <sub>L</sub> 1 not connected, R <sub>L</sub> 2 = 1.6 k $\Omega$ , See Figure 5		17	ns
<sup>t</sup> w(NR)	Receiver noise rejection pulse duration	Bn	An	$\overline{CS}$ at 0.8 V, T/R at 0.8 V, RL1 = 390 Ω, RL2 = 1.6 kΩ, CL = 30 pF, VL = 5 V, See Figure 6	3		ns



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# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER		PARAMETER FROM TO TEST COND		TEST CONDITIONS	SN75ALS057 DRIVER			UNIT	
			(001P01)		MIN	TYP <sup>†</sup>	MAX			
<sup>t</sup> PLH1	Propagation delay time, low-to-high-level output	TE	Pn	Dn, En, $\overline{RE}$ at 2 V, V <sub>L</sub> = 2 V,			24	20		
<sup>t</sup> PHL1	Propagation delay time, high-to-low-level output		Bn		RL2 not connected, RL1 = 18 Ω, See Figure 2, CL = 30 pF			20	ns	
<sup>t</sup> PLH2	Propagation delay time, low-to-high-level output		Dn or En	Bn	TE at 0.8 V, $\overline{\text{RE}}$ at 2 V, V <sub>1</sub> = 2 V, R <sub>1</sub> 1 = 18 $\Omega$ ,			19		
<sup>t</sup> PHL2	Propagation delay time, high-to-low-level output	DNOLEN		$R_L^2$ not connected, $C_L = 30 \text{ pF}$ , See Figure 2			18	ns		
<sup>t</sup> TLH	Transition time, low-to-high-level output			Descr	Bn	$\overline{\text{RE}}$ at 2 V, V <sub>L</sub> = 2 V, TE at 0.8 V, R <sub>L</sub> 1 = 18 Ω,,	1	3	11	
<sup>t</sup> THL	Transition time, high-to-low-level output	Dn or En	БU	$R_L 2$ not connected, $C_L = 30 \text{ pF}$ , See Figure 2	1	3	6	ns		

<sup>†</sup> Typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25^{\circ}C$ .

# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75AI RECE		UNIT
					MIN	MAX	
<sup>t</sup> PLH4	Propagation delay time, low-to-high-level output	Bn	Rn	$\overline{\text{RE}}$ at 0.8 V, $\overline{\text{TE}}$ at 2 V, V <sub>L</sub> = 5 V,		18	ns
<sup>t</sup> PHL4	Propagation delay time, high-to-low-level output	Ы	KII	$R_L 1 = 390 \Omega$ , $R_L 2 = 1.6 k\Omega$ , $C_L = 30 pF$ , See Figure 4		18	115
<sup>t</sup> PLZ2	Output disable time from low level	RE	Rn	Bn at 2 V, $\overline{\text{TE}}$ at 2 V, V <sub>L</sub> = 5 V, C <sub>L</sub> = 5 pF, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 not connected, See Figure 5		18	ns
<sup>t</sup> PZL2	Output enable time to low level	RE	Rn	Bn at 2 V, $\overline{\text{TE}}$ at 2 V, V <sub>L</sub> = 5 V, C <sub>L</sub> = 30 pF, R <sub>L</sub> 1 = 390 Ω, R <sub>L</sub> 2 = 1.6 kΩ, See Figure 5		15	ns
<sup>t</sup> PHZ2	Output disable time from high level	RE	Rn	Bn at 0.8 V, $\overline{\text{TE}}$ at 2 V, VL = 0, CL = 5 pF, RL1 = 390 $\Omega$ , RL2 not connected, See Figure 5		17	ns
<sup>t</sup> PZH2	Output enable time to high level	RE	Rn	Bn at 0.8 V, $\overline{\text{TE}}$ at 2 V, VL = 0, CL = 30 pF, RL1 not connected, RL2 = 1.6 k $\Omega$ , See Figure 5		17	ns
<sup>t</sup> w(NR)	Receiver noise rejection pulse duration	Bn	Rn	TE at 2 V, RE at 0.8 V, V <sub>L</sub> = 0, R <sub>L</sub> 1 = 390 $\Omega$ , R <sub>L</sub> 2 = 1.6 k $\Omega$ , C <sub>L</sub> = 30 pF, See Figure 6	3		ns



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# switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	SN75AL DRIVER RECEI	UNIT	
					MIN	MAX	
<sup>t</sup> PLH6	Propagation delay time, low-to-high-level output	Dn	Rn	$\overline{\text{RE}}$ at 0.8 V, $\overline{\text{TE}}$ at 0.8 V, $R_{L}$ 1 = 390 $\Omega$ ,		40	ns
<sup>t</sup> PHL6	Propagation delay time, high-to-low-level output			$R_L 2 = 1.6 \text{ k}\Omega$ , $C_L = 30 \text{ pF}$ , See Figure 7		40	

#### PARAMETER MEASUREMENT INFORMATION

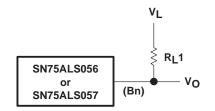
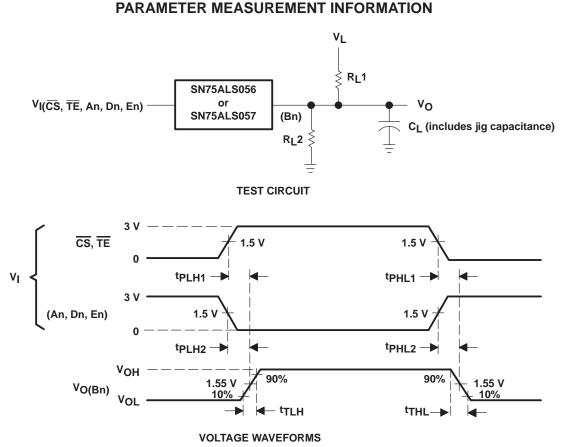


Figure 1. Driver Low-Level-Output-Voltage Test Circuit



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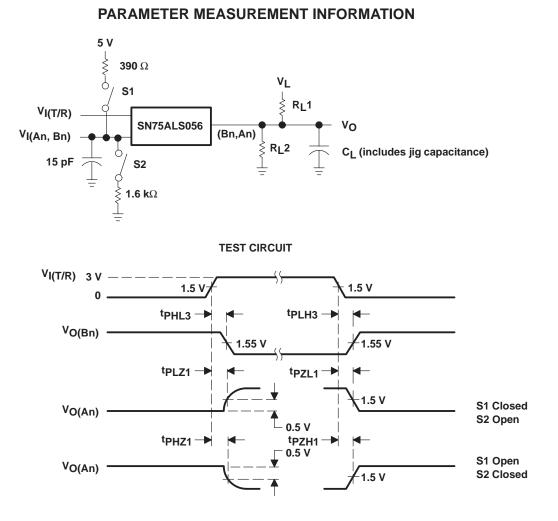


NOTE A:  $t_f = t_f \le 5$  ns from 10% to 90%





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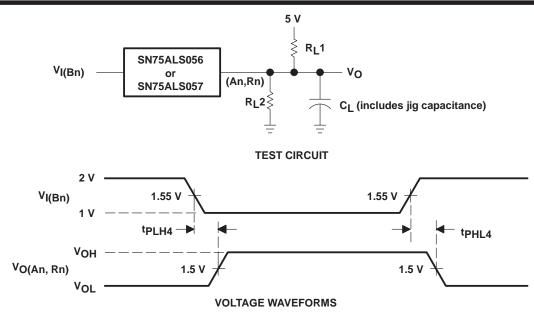
VOLTAGE WAVEFORMS

NOTE A:  $t_r = t_f \le 5$  ns from 10% to 90%

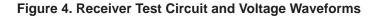
Figure 3. Propagation Delay From T/R to An or Bn Test Circuit and Voltage Waveforms

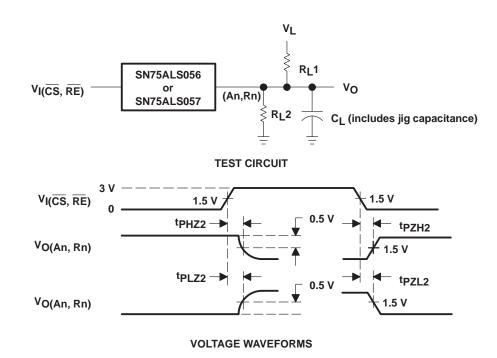


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NOTE A:  $t_r = t_f \le 5$  ns from 10% to 90%



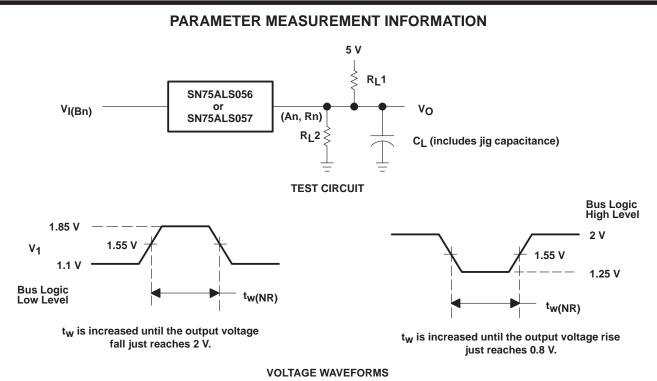


NOTE A:  $t_{f} = t_{f} \le 5$  ns from 10% to 90%



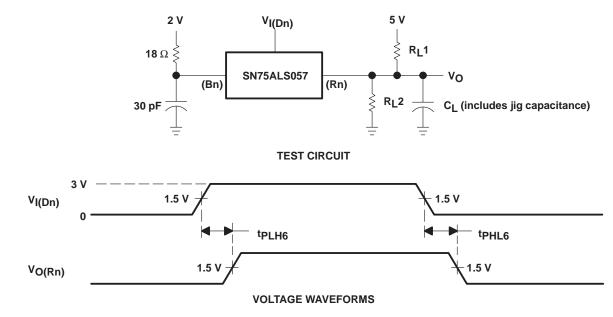


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NOTE A:  $t_r = t_f \le 5$  ns from 10% to 90%





NOTE A:  $t_r = t_f \le 5$  ns from 10% to 90%







10-Jun-2014

#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN75ALS056DW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75ALS056	Samples
SN75ALS056DWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75ALS056	Samples
SN75ALS056N	ACTIVE	PDIP	Ν	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	SN75ALS056N	Samples
SN75ALS057DW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75ALS057	Samples
SN75ALS057DWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	0 to 70	75ALS057	Samples
SN75ALS057N	ACTIVE	PDIP	Ν	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	0 to 70	SN75ALS057N	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free (RoHS):** TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



## PACKAGE OPTION ADDENDUM

10-Jun-2014

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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## PACKAGE MATERIALS INFORMATION

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#### TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN75ALS056DWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN75ALS057DWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

TEXAS INSTRUMENTS

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## PACKAGE MATERIALS INFORMATION

3-Jan-2013



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN75ALS056DWR	SOIC	DW	20	2000	367.0	367.0	45.0
SN75ALS057DWR	SOIC	DW	20	2000	367.0	367.0	45.0

## N (R-PDIP-T\*\*)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- $\triangle$  The 20 pin end lead shoulder width is a vendor option, either half or full width.



# **DW0020A**



## **PACKAGE OUTLINE**

#### SOIC - 2.65 mm max height

SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



## DW0020A

# **EXAMPLE BOARD LAYOUT**

#### SOIC - 2.65 mm max height

SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



## DW0020A

## **EXAMPLE STENCIL DESIGN**

#### SOIC - 2.65 mm max height

SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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